TFSC
Instrument

Active thin film quality optimization for Silicon and Organic

Photo-carrier diffusion length measurements : L_D

- ✔ **Less than 5 mn** measurement
- ✔ **Direct** measurement : no need to measure carrier mobility and lifetime to deduce L_D
- ✔ **Direct** link to device performances

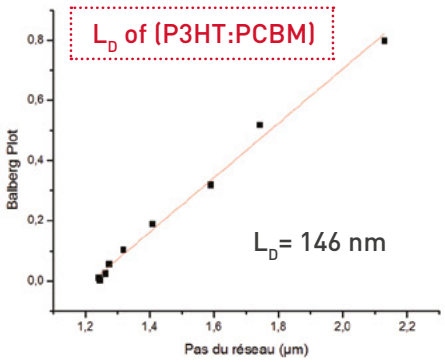
PARTNERS

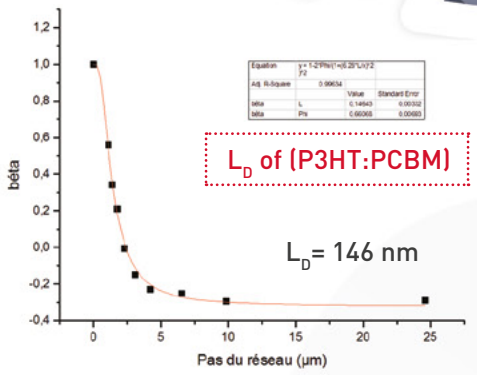
cnrs Supélec GEP

www.tfscinstrument.com

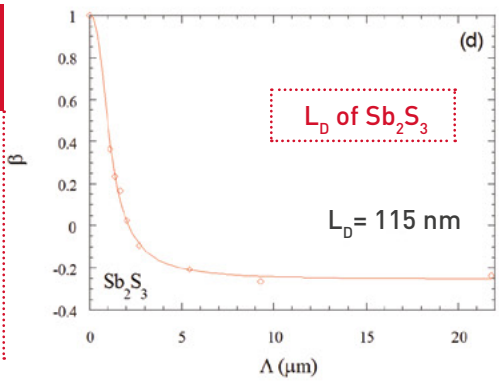
Typical data

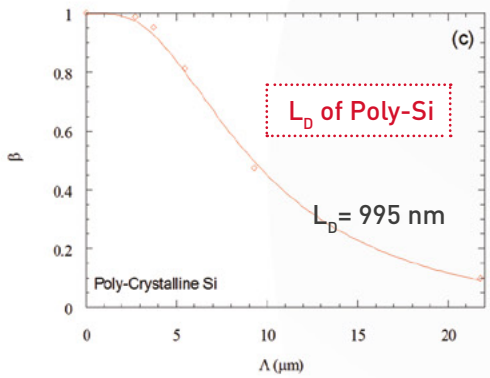
• Measurement on Organic layers:
• Successful measurement
• First data to be published worldwide



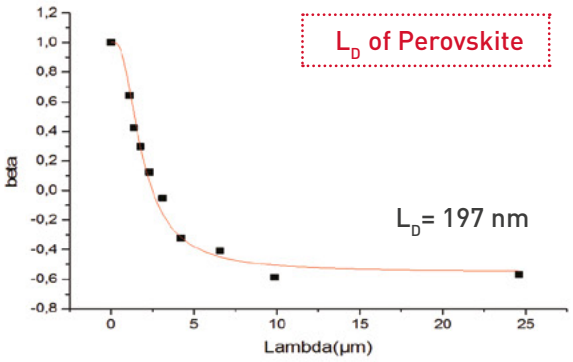


Measurements on non-organic layers





Measurements on Perovskite layers



Product features and specifications

• Measurement based on SSPG method (Steady State Phocarrier Grating)
• Measurement range of diffusion length: from 10 nm to 10 µm
• Material type: Non-organic, Organic(BHJ), Perovskite...
• Sample conditions: from atmosphere to vacuum, under variable temperatures
• Option 1: sample under vacuum
• Option 2: sample heated up to 200 °C
• Equipment size: 604x754x327 mm

To contact us

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